

ABSTRACT OF THE DISCLOSURE

An integrated circuit for locating failure process layers. The circuit has a substrate with a scan chain disposed therein, having scan cells connected to form a series chain.
5 Each connection is formed according to a layout constraint of a minimum dimension provided by design rules for an assigned routing layer. Since the connection in the assigned routing layer is constrained to a minimum, the scan chain is vulnerable to variations in processes relevant to the assigned routing
10 layer. The scan chain makes it easier to locate processes causing low yield rate of the scan chain.